

AA or ICP - Which do you choose?

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Introduction

For many analysts Atomic Absorption Spectrometry (AAS) is a well established and understood technique. However, even though Inductively Coupled Plasma Emission Spectrometry (ICP-ES) instrumentation has been commercially available for over a decade, the technique has proven to be more complex. This article discusses the main differences between the two techniques.

AAS vs ICP

The basic difference between the two techniques is that one relies upon an atomic absorption process while the other is an atomic/ionic emission spectroscopic technique. The next essential difference is the means by which the atomic or ionic species are generated. A combustion flame or graphite furnace is typically used for AA while ICP-ES uses a plasma.

The typical maximum temperature for an air/acetylene flame is 2 300 °C while for nitrous oxide acetylene, it is 2 900 °C. Temperatures as high as 10 000 K can be reached in an argon plasma.

Detection limits

The comparison of detection limits in table 1 highlights the following differences:

- (i) Furnace AA detection limits are generally better in all cases where the element can be atomized.
- (ii) Detection limits for Group I elements (e.g. Na, K) are generally better by flame AAS than by ICP.
- (iii) Detection limits for refractory elements (e.g. B, Ti, V, Al) are better by ICP than by flame AAS.
- (iv) Non metals such as sulfur, nitrogen, carbon, and the halogens (e.g. I, Cl, Br) can only be determined by ICP.

While it is possible to determine phosphorous by AAS, its detection limit by ICP is more than three orders of magnitude better.

Optimum detection of non metals such as S, N and halogens by ICP-ES can only be achieved if a vacuum monochromator, with purged transfer optics, is used. The optics must be purged to exclude atmospheric oxygen and eliminating its absorption.

Sulfur can be measured at 180.73 nm by purging the monochromator. To detect the primary aluminium wavelength at 167.08 nm, the monochromator must first be evacuated, then purged with the inert plasma gas.

Note that a continuous flow vapor generation accessory can be used with either ICP-ES or AAS for improved detection limits for As, Se, Hg, Sb, Bi and Ge.

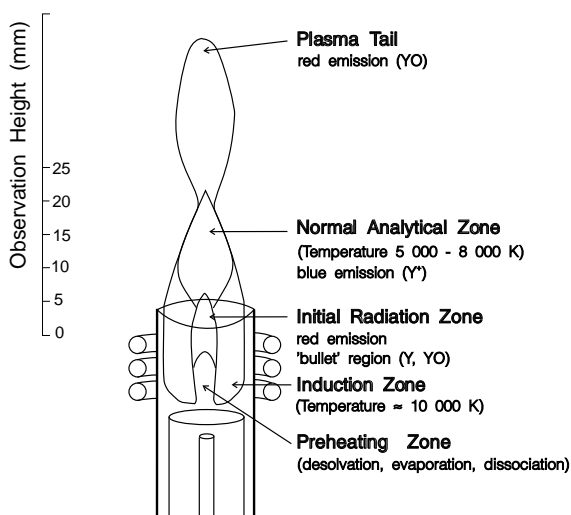


Figure 1: A plasma used for emission spectrometry. The regions refer to those seen when a Yttrium solution is introduced.

Sample throughput

In ICP-ES, the rate at which samples may be determined depends on the type of instrument: both simultaneous and sequential ICP spectrometers are available. Most ICP spectrometers purchased are the sequential type, providing maximum flexibility of choice of element and analytical wavelength. Surveys have shown that most analysts are interested in 6-15 elements per sample and choose to pump the sample (which increases washout times) to improve precision and accuracy by minimizing viscosity effects. Simultaneous ICP spectrometers demonstrate an advantage in analytical speed over sequential ICP spectrometers when more than 6 elements/sample are measured.

If a 'one off' sample is presented for a few elements, flame AAS is faster. However, with flame equilibration time, program recall and monochromator condition changes, the cross over point where sequential ICP becomes faster than AAS is approximately 6 elements/sample for routine analysis.

Unattended operation

Flame AAS cannot be left completely unattended for safety reasons. An ICP-ES instrument or graphite furnace AA can be left to run overnight as no combustible gases are involved, effectively increasing the working day from 8 hours to 24 hours.

Linear dynamic range

The inductively coupled plasma is doughnut shaped (with a 'hollow' centre). The sample aerosol enters the base of the plasma via the injector tube. The 'optical thinness' of the ICP results in little self absorption and is the main reason for the large linear dynamic range of about 10^5 . For example, copper can be measured at the 324.75 nm wavelength from its detection limit of about 0.002 ppm to over 200 ppm. In ICP, extrapolation of two point calibrations can be accurately used to achieve orders of magnitude above the top standard. This compares to a linear dynamic range of typically 10^3 for AAS.

Interferences

Chemical

Chemical interferences are relatively common in AA, especially with graphite furnace AA, but may be minimized with chemical modifiers.

ICP-ES is almost free from chemical interferences. The chemical bonds that still exist at below 3000 °C are completely ruptured at above 6000 °C. The high temperatures reached in a plasma eliminate chemical interferences, which accounts (for the most part) for the better detection limits achieved for refractory elements.

Ionization

The ICP contains a large number of free electrons, so ionization interferences for most applications are virtually nonexistent. Ionization interferences can be encountered when determining elements in matrices that contain very high concentrations of Group I elements (e.g. Na & K). However, these effects can be minimized by optimizing the plasma viewing height.

Ionization interferences may also be found in AAS, e.g. when measuring certain Group II elements in a nitrous oxide flame. An ionization buffer such as Cs, Li or K can be added to both samples and standards to minimize this effect.

Spectral

The optical requirements of AAS are fairly simple. The monochromator only needs to distinguish a spectral line emitted from the hollow cathode lamp from other nearby lines. The lamp itself only emits a few spectral lines. Most elements require 0.5 nm resolution with only iron, nickel and cobalt of the common elements requiring 0.2 nm or better.

In ICP-ES, the rich spectra present in the plasma means that there is a greater possibility of spectral interference. Spectral resolutions of 0.010 nm or better are required to resolve nearby interfering lines from the atomic and ionic analytical emission signals of interest.

Spectral interference in sequential ICP spectrometers can, in most cases, be overcome by selecting a different elemental wavelength with similar detection limits. With simultaneous ICP spectrometers, the elements and the wavelengths which may be determined are fixed at the time of purchase, and an alternative line may not be available. In this case, inter-element correction may be used to minimize the spectral interference.

Physical

These interferences relate to the different properties of various samples and can affect sample transport and droplet formation. ICP tends to be more susceptible to such interference because of the smaller droplet size required and lower transport efficiency.

Precision

Precision can be termed short term (or within-run) and long term (over a period of one day). For AAS a precision of 0.1-1% is typical for the short term, but recalibration is required over a longer period. With ICP-ES the short term precision is typically 0.3-2%, but precisions of 2-5% are not uncommon over an 8 hour period without recalibration.

One technique used to eliminate backlash in the grating drive mechanism of ICP spectrometers is by scanning and measuring at the same time. This method of measurement can be termed as 'measurement on the move' and effectively results in poor short term precision. A more recent method drives the grating to a wavelength near the analytical peak. A refractor scan is then performed over a smaller wavelength region in order to identify and locate the peak position. Finally the refractor plate is repositioned 'at the peak' where the replicate measurements are then performed. This method offers better precision.

Analytical requirements

Before deciding which technique is appropriate, the chemist must define both present and future analytical requirements. That is:

- (a) Number of samples/week?
- (b) What matrices need to be analyzed? e.g. steels, bronzes, effluents, soils, etc.
- (c) How many elements need to be determined for each sample type?
- (d) What are the typical sample volumes?
- (e) What elements need to be determined?
- (f) What concentration ranges are present in the matrices?
- (g) Would an Internal Standard be useful? For example, where the samples may change in viscosity from sample to sample, e.g. battery acid analysis.
- (h) What expertise do the operators have?
- (i) How much money is available to purchase or lease costs/month?
- (j) Cost of ownership and running costs. Can the user afford an automated AAS or ICP-ES, or is a simple AAS sufficient?

The answers to these questions will help you to decide which is the preferred technique. Sometimes the answer is further complicated by the fact that neither flame AAS nor ICP-ES will satisfy all requirements. You may find, as many do, that both an ICP-ES **and** a furnace AAS will be necessary to meet the analytical requirements.

AAS v ICP - A quick guide

ICP-OES Flame AAS Furnace AAS

Detection Limits	Best for : Refractories Non metals P, S, B, Al V, Ba, Ti	Best for : Group I metals Na, K Volatile elements Pb, Zn Rare Earths	Best for : All elements except : B,W,U, Refractories, eg P, S Halogens
Sample Throughput	Best if more than 6 elements/sample	Best if less than 6 elements/sample	Slow (typically 4 mins/element)
Linear Dynamic Range	10 ⁵	10 ³	10 ²
Precision			
Short Term	0.3 - 2%	0.1 - 1%	0.5 - 5%
Long Term (over 8 hrs)	Less than 5%		
Interferences			
Spectral	Many	Virtually None	Minimal
Chemical	Virtually None	Some	Many
Ionization	Minimal	Some	Minimal
Operating costs	High	Low	Relatively high
Combustible gases	No	Yes	No

Table 1

Guide to ICP/AAS Analytical Values

Element		ICP		Flame AA		Zeeman Furnace AA					
		λ (nm)		Detection	Characteristic	Detection	Flame	Characteristic ^d		MSR	El
		AA	ICP	Limit	Conc	Limit	Type	Conc ^a	Mass		
				$\mu\text{g/L}$	$\mu\text{g/L}$	$\mu\text{g/L}$		$\mu\text{g/L}$	pg	%	
Silver	Ag	328.1	328.068	3	30	2	Air	0.035	0.7	97	
Aluminium	Al	309.3	167.081	1.5	800	30	N ₂ O	0.25	5	100	Al
Arsenic	As	193.7	188.985	12	500	300	N ₂ O	0.5	10*	86	As
Gold	Au	242.8	267.595	5.5	100	10	Air	0.22	4.4	94	Au
Boron	B	249.8	249.773	1.5	8000	500	N ₂ O	43	855*	70	B
Barium	Ba	553.6	455.403	0.07	200	20	N ₂ O	0.85	17	100	Ba
Beryllium	Be	234.9	313.042	0.2	15	1	N ₂ O	0.025	0.5	64	Be
Bismuth	Bi	223.1	223.061	12	200	50	Air	0.45	9	88	Bi
Bromine	Br		163.340	6000							Br
Carbon	C		247.856	65						-	C
Calcium	Ca	422.7	393.366	0.03	10	1	N ₂ O	0.03	0.6	94	Ca
Cadmium	Cd	228.8	228.802	1.5	10	2	Air	0.01	0.2*	87	Cd
Cerium	Ce	520.0	418.660	7.5	100000	100000	N ₂ O			-	Ce
Chlorine	Cl		725.665	200000						-	Cl
Cobalt	Co	240.7	228.616	5	50	5	Air	0.21	4.2	98	Co
Chromium	Cr	357.9	267.716	4	50	6	N ₂ O	0.075	1.5	100	Cr
Cesium	Cs	852.1	455.531	3200	20	4	Air	0.55	11	58	Cs
Copper	Cu	324.7	324.754	2	30	3	Air	0.3	6	84	Cu
Dysprosium	Dy	421.2	353.170	0.3	600	30	N ₂ O	2.3	45	100	Dy
Erbium	Er	400.8	337.271	0.7	500	50	N ₂ O	5	100	100	Er
Europium	Eu	459.4	381.967	0.3	300	1.5	N ₂ O	1.3	25	100	Eu
Iron	Fe	248.3	259.940	1.5	50	6	Air	0.06	1.2	97	Fe
Gallium	Ga	294.4	417.206	6.5	800	100	Air	0.23	4.5*	80	Ga
Gadolinium	Gd	368.4	342.247	2.5	20000	2000	N ₂ O			-	Gd
Germanium	Ge	265.1	265.118	13	1000	200	N ₂ O	0.45	9*	100	Ge
Hafnium	Hf	307.3	264.141	4	10000	2000	N ₂ O			-	Hf
Mercury	Hg	253.7	184.950	8.5	1500	200	Air	7.5	150*	69	Hg
Holmium	Ho	410.4	345.600	0.5	700	40	N ₂ O			-	Ho
Iodine	I		178.276	60							I
Indium	In	303.9	325.609	18	150	40	Air	0.35	7.0*	100	In
Iridium	Ir	208.9	224.268	3.5	800	500	Air	6.8	135	97	Ir
Potassium	K	766.5	766.490	10	7	3	Air	0.02	0.4	90	K
Lanthanum	La	550.1	379.478	0.02	40000	2000	N ₂ O			-	La
Lithium	Li	670.8	670.784	0.6	20	2	Air	0.2	4	49	Li
Lutetium	Lu	336.0	261.542	0.05	7000	300	N ₂ O			-	Lu
Magnesium	Mg	285.2	279.553	0.1	3	0.3	Air	0.01	0.2	75	Mg
Manganese	Mn	279.5	257.610	0.3	20	2	Air	0.03	0.6	92	Mn
Molybdenum	Mo	313.3	202.030	4	300	20	N ₂ O	0.35	7	96	Mo
Nitrogen	N		174.272	50 000							N
Sodium	Na	589.0	588.995	1	3	0.2	Air	0.005	0.1	92	Na
Niobium	Nb	334.9	309.418	4	20000	2000	N ₂ O			-	Nb
Neodymium	Nd	492.5	401.225	2	6000	1000	N ₂ O			-	Nd
Nickel	Ni	232.0	231.604	5.5	70	10	Air	0.24	4.8	98	Ni
Osmium	Os	290.9	225.585	5	1000	100	N ₂ O			-	Os
Phosphorous	P	213.6	177.499	18	120000	40000	N ₂ O	110	2200*	69	P
Lead	Pb	217.0	220.353	14	100	10	Air	0.28	5.5	92	Pb
Palladium	Pd	244.8	340.458	7	50	10	Air	0.43	8.6	100	Pd
Praseodymium	Pr	495.1	417.939	0.8	20000	10000	N ₂ O			-	Pr
Platinum	Pt	265.9	265.945	20	100	100	Air	3.5	70	82	Pt
Rubidium	Rb	780.0	780.023	35	500	10	Air	0.05	1	90	Rb
Rhenium	Re	346.1	227.525	11	8000	1000	N ₂ O			-	Re

Guide to ICP/AAS Analytical Values

Element		ICP		Flame AA		Zeeman Furnace AA					
		λ (nm)		Detection	Characteristic	Detection	Flame	Characteristic ^d	MSR		El
		AA	ICP	Limit	Conc	Limit	Type	Conc ⁺	Mass	%	
				$\mu\text{g/L}$	$\mu\text{g/L}$	$\mu\text{g/L}$		$\mu\text{g/L}$	pg		
Rhodium	Rh	343.5	343.489	5	100	5	Air	0.4	8	95	
Ruthenium	Ru	349.9	267.876	5.5	400	100	Air	0.75	15	100	Ru
Sulphur	S		180.734	20						-	S
Antimony	Sb	217.6	217.581	18	300	40	Air	0.5	10	96	Sb
Scandium	Sc	391.2	361.384	0.4	300	50	N ₂ O			-	Sc
Selenium	Se	196.0	196.026	37	1000	500	N ₂ O	0.7	14*	92	Se
Silicon	Si	251.6	251.611	5	1500	300	N ₂ O	0.75	15	100	Si
Samarium	Sm	429.7	442.434	7	6000	1000	N ₂ O			-	Sm
Tin	Sn	235.5	242.949	15	700	100	N ₂ O	0.5	10*	93	Sn
Strontium	Sr	460.7	407.771	0.02	40	2	N ₂ O	0.1	2	94	Sr
Tantalum	Ta	271.5	268.517	9	10000	2000	N ₂ O			-	Ta
Terbium	Tb	432.7	350.917	5	7000	700	N ₂ O	0.18	3.5	90	Tb
Tellurium	Te	214.3	214.281	27	200	30	Air	0.45	9*	93	Te
Thorium	Th		274.716	17						-	Th
Titanium	Ti	364.3	334.941	0.6	1000	100	N ₂ O	2.5	50	100	Ti
Thallium	Tl	276.8	351.924	16	200	20	Air	0.75	15	63	Tl
Thulium	Tm	371.8	346.220	1.5	300	20	N ₂ O			-	Tm
Uranium	U	358.5	385.958	18	100000	40000	N ₂ O			-	U
Vanadium	V	318.5	309.311	2	700	100	N ₂ O	1.1	22	79	V
Tungsten	W	255.1	239.709	17	5000	1000	N ₂ O			-	W
Yttrium	Y	410.2	371.030	0.2	2000	200	N ₂ O			-	Y
Ytterbium	Yb	398.8	328.937	0.3	60	4	N ₂ O	0.15	3	97	Yb
Zinc	Zn	213.9	213.856	0.9	8	1.0	Air	0.0075	0.15	92	Zn
Zirconium	Zr	360.1	339.198	1.5	9000	1000	N ₂ O			-	Zr

NOTES :

* Modifier used to obtain these results.

+ 20 μL injection

The Characteristic Masses listed were determined in aqueous solution using maximum heating rate in argon with zero gas flow during atomization.

For Deuterium Furnace systems, the equivalent Characteristic Concentration and Characteristic Mass is easily calculated using the following conversion:

$$\text{CMn} = \text{CMz} \times \text{MSR} (\%) / 100 \quad \text{CCn} = \text{CCz} \times \text{MSR} (\%) / 100$$

where:

CMn = Characteristic Mass for Deuterium Furnace Systems

CMz = Characteristic Mass for Zeeman Furnace Systems (from Table above)

MSR = Magnetic Sensitivity Ratio (as % from Table above)

CCn = Characteristic Concentration for Deuterium Furnace Systems

CCz = Characteristic Concentration for Zeeman Furnace Systems (from Table above).